

LM5109B High Voltage 1A Peak Half Bridge Gate Driver

Check for Samples: LM5109B

FEATURES

- Drives both a high-side and low-side N-Channel MOSFET
- 1A peak output current (1.0A sink / 1.0A source)
- Independent TTL compatible inputs
- Bootstrap supply voltage to 108V DC
- Fast propagation times (30 ns typical)
- Drives 1000 pF load with 15ns rise and fall times
- Excellent propagation delay matching (2 ns

typical)

- · Supply rail under-voltage lockout
- Low power consumption
- Pin compatible with ISL6700

TYPICAL APPLICATIONS

- Current Fed push-pull converters
- Half and Full Bridge power converters
- Solid state motor drives
- Two switch forward power converters

DESCRIPTION

The LM5109B is a cost effective, high voltage gate driver designed to drive both the high-side and the low-side N-Channel MOSFETs in a synchronous buck or a half bridge configuration. The floating high-side driver is capable of working with rail voltages up to 90V. The outputs are independently controlled with TTL compatible input thresholds. The robust level shift technology operates at high speed while consuming low power and providing clean level transitions from the control input logic to the high-side gate driver. Under-voltage lockout is provided on both the low-side and the high-side power rails. The device is available in the SOIC-8 and the thermally enhanced LLP-8 packages.

Package

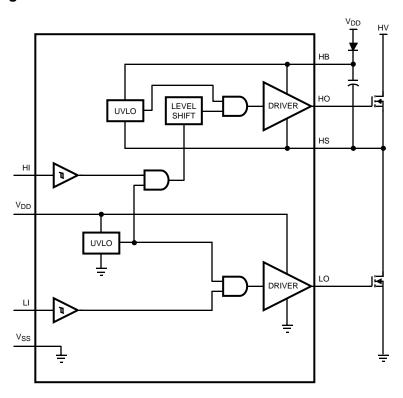
- SOIC-8
- LLP-8 (4 mm x 4 mm)

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Simplified Block Diagram



Connection Diagrams

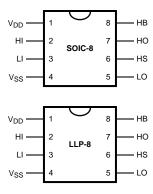


Table 1. Pin Descriptions

Pi	Pin #				Description	Annihatian Information
SO-8	LLP-8	Name	Description	Application Information		
1	1	V _{DD}	Positive gate drive supply	Locally decouple to V _{SS} using low ESR/ESL capacitor located as close to IC as possible.		
2	2	HI	High side control input	The HI input is compatible with TTL input thresholds. Unused HI input should be tied to ground and not left open.		
3	3	LI	Low side control input	The LI input is compatible with TTL input thresholds. Unused LI input should be tied to ground and not left open.		
4	4	V _{SS}	Ground reference	All signals are referenced to this ground.		
5	5	LO	Low side gate driver output	Connect to the gate of the low-side N-MOS device.		
6	6	HS	High side source connection	Connect to the negative terminal of the bootstrap capacitor and to the source of the high-side N-MOS device.		
7	7	НО	High side gate driver output	Connect to the gate of the high-side N-MOS device.		



Table 1. Pin Descriptions (continued)

Pi	Pin # O-8 LLP-8 Name Description		Description	Application Information		
SO-8			Description	Application Information		
8	8	НВ	High side gate driver positive supply rail	Connect the positive terminal of the bootstrap capacitor to HB and the negative terminal of the bootstrap capacitor to HS. The bootstrap capacitor should be placed as close to IC as possible.		



These devices have limited built-in ESD protection. The leads should be shorted together or the device placed in conductive foam during storage or handling to prevent electrostatic damage to the MOS gates.

Absolute Maximum Ratings (1)

V _{DD} to V _{SS}	-0.3V to 18V
HB to HS	-0.3V to 18V
LI or HI to V _{SS}	-0.3V to V _{DD} +0.3V
LO to V _{SS}	-0.3V to V _{DD} +0.3V
HO to V _{SS}	V_{HS} =0.3V to V_{HB} +0.3V
HS to V _{SS} ⁽²⁾	-5V to 90V
HB to V _{SS}	108V
Junction Temperature	-40°C to +150°C
Storage Temperature Range	-55°C to +150°C
ESD Rating HBM (3)	1.5 kV

- (1) Absolute Maximum Ratings indicate limits beyond which damage to the component may occur. Operating Ratings are conditions under which operation of the device is guaranteed. Operating Ratings do not imply guaranteed performance limits. For guaranteed performance limits and associated test conditions, see the Electrical Characteristics tables.
- (2) In the application the HS node is clamped by the body diode of the external lower N-MOSFET, therefore the HS voltage will generally not exceed -1V. However in some applications, board resistance and inductance may result in the HS node exceeding this stated voltage transiently. If negative transients occur on HS, the HS voltage must never be more negative than V_{DD} 15V. For example, if V_{DD} = 10V, the negative transients at HS must not exceed -5V.
- (3) The human body model is a 100 pF capacitor discharged through a $1.5k\Omega$ resistor into each pin.

Recommended Operating Conditions

V_{DD}	8V to 14V
HS ⁽¹⁾	-1V to 90V
НВ	V_{HS} +8V to V_{HS} +14V
HS Slew Rate	< 50 V/ns
Junction Temperature	-40°C to +125°C

(1) In the application the HS node is clamped by the body diode of the external lower N-MOSFET, therefore the HS voltage will generally not exceed -1V. However in some applications, board resistance and inductance may result in the HS node exceeding this stated voltage transiently. If negative transients occur on HS, the HS voltage must never be more negative than V_{DD} - 15V. For example, if V_{DD} = 10V, the negative transients at HS must not exceed -5V.



Electrical Characteristics

Specifications in standard typeface are for T_J = +25°C, and those in **boldface type** apply over the full **operating junction temperature range**. Unless otherwise specified, V_{DD} = V_{HB} = 12V, V_{SS} = V_{HS} = 0V, No Load on LO or HO ⁽¹⁾.

Symbol	Parameter	Conditions	Min	Тур	Max	Units
SUPPLY C	URRENTS		ı		'	
I _{DD}	V _{DD} Quiescent Current	LI = HI = 0V		0.3	0.6	mA
I _{DDO}	V _{DD} Operating Current	f = 500 kHz		1.8	2.9	mA
I _{HB}	Total HB Quiescent Current	LI = HI = 0V		0.06	0.2	mA
I _{HBO}	Total HB Operating Current	f = 500 kHz		1.4	2.8	mA
I _{HBS}	HB to V _{SS} Current, Quiescent	V _{HS} = V _{HB} = 90V		0.1	10	μΑ
I _{HBSO}	HB to V _{SS} Current, Operating	f = 500 kHz		0.5		mA
INPUT PIN	S LI and HI					
V_{IL}	Low Level Input Voltage Threshold		0.8	1.8		V
V_{IH}	High Level Input Voltage Threshold			1.8	2.2	V
R _I	Input Pulldown Resistance		100	200	500	kΩ
UNDER VO	LTAGE PROTECTION					
V_{DDR}	V _{DD} Rising Threshold	V _{DDR} = V _{DD} - V _{SS}	6.0	6.7	7.4	V
V_{DDH}	V _{DD} Threshold Hysteresis			0.5		V
V_{HBR}	HB Rising Threshold	V _{HBR} = V _{HB} - V _{HS}	5.7	6.6	7.1	V
V_{HBH}	HB Threshold Hysteresis			0.4		V
LO GATE I	DRIVER					
V_{OLL}	Low-Level Output Voltage	I_{LO} = 100 mA V_{OHL} = $V_{LO} - V_{SS}$		0.38	0.65	V
V_{OHL}	High-Level Output Voltage	$I_{LO} = -100 \text{ mA},$ $V_{OHL} = V_{DD} - V_{LO}$		0.72	1.20	V
I _{OHL}	Peak Pullup Current	V _{LO} = 0V		1.0		Α
I _{OLL}	Peak Pulldown Current	V _{LO} = 12V		1.0		Α
HO GATE	DRIVER					
V_{OLH}	Low-Level Output Voltage	I_{HO} = 100 mA V_{OLH} = V_{HO} – V_{HS}		0.38	0.65	V
V_{OHH}	High-Level Output Voltage	I _{HO} = -100 mA V _{OHH} = V _{HB} - V _{HO}		0.72	1.20	V
I _{OHH}	Peak Pullup Current	V _{HO} = 0V		1.0		Α
I _{OLH}	Peak Pulldown Current	V _{HO} = 12V		1.0		Α
THERMAL	RESISTANCE					
θ_{JA}	Junction to Ambient	SOIC-8 ⁽²⁾ , ⁽³⁾		160		00 441
		LLP-8 ⁽²⁾ , ⁽³⁾		40		°C/W

⁽¹⁾ Min and Max limits are 100% production tested at 25°C. Limits over the operating temperature range are guaranteed through correlation using Statistical Quality Control (SQC) methods. Limits are used to calculate National's Average Outgoing Quality Level (AOQL).

⁴ layer board with Cu finished thickness 1.5/1/1/1.5 oz. Maximum die size used. 5x body length of Cu trace on PCB top. 50 x 50mm ground and power planes embedded in PCB. See Application Note AN-1187. The θ_{JA} is not a constant for the package and depends on the printed circuit board design and the operating conditions.



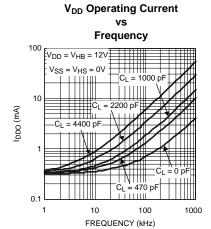
Switching Characteristics

Specifications in standard typeface are for T_J = +25°C, and those in **boldface type** apply over the full **operating junction temperature range**. Unless otherwise specified, V_{DD} = V_{HB} = 12V, V_{SS} = V_{HS} = 0V, No Load on LO or HO.

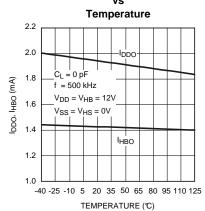
Symbol	Parameter	Conditions	Min	Тур	Max	Units
t _{LPHL}	Lower Turn-Off Propagation Delay (LI Falling to LO Falling)			30	56	ns
t _{HPHL}	Upper Turn-Off Propagation Delay (HI Falling to HO Falling)			30	56	ns
t _{LPLH}	Lower Turn-On Propagation Delay (LI Rising to LO Rising)			32	56	ns
t _{HPLH}	Upper Turn-On Propagation Delay (HI Rising to HO Rising)			32	56	ns
t _{MON}	Delay Matching: Lower Turn-On and Upper Turn-Off			2	15	ns
t _{MOFF}	Delay Matching: Lower Turn-Off and Upper Turn-On			2	15	ns
t _{RC} , t _{FC}	Either Output Rise/Fall Time	C _L = 1000 pF		15	-	ns
t _{PW}	Minimum Input Pulse Width that Changes the Output			50		ns



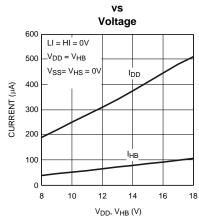
Typical Performance Characteristics



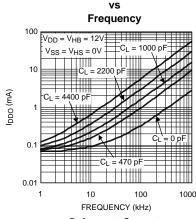
Operating Current vs



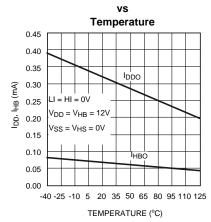
Quiescent Current



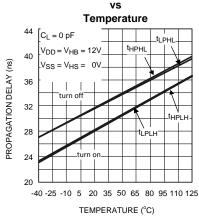
HB Operating Current



Quiescent Current



Propagation Delay

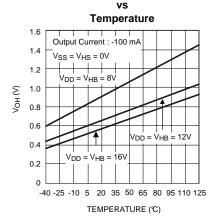


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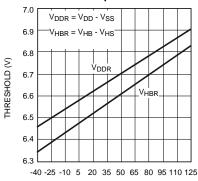
Typical Performance Characteristics (continued)

LO and HO High Level Output Voltage

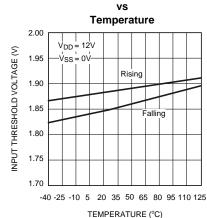


Undervoltage Rising Thresholds vs

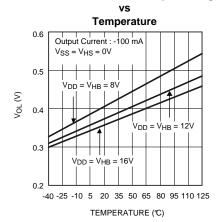
Temperature 7.0 V_{DDR} = V_{DD} - V_{SS}



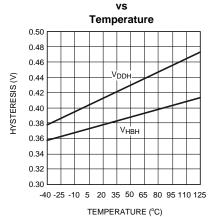
TEMPERATURE (°C) Input Thresholds



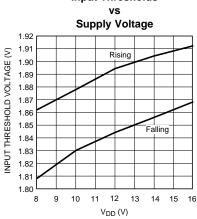
LO and HO Low Level Output Voltage



Undervoltage Hysteresis



Input Thresholds

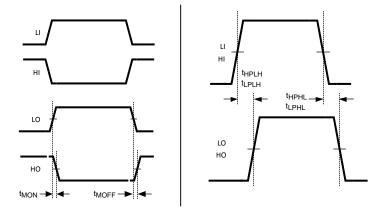


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Timing Diagram



Layout Considerations

Optimum performance of high and low-side gate drivers cannot be achieved without taking due considerations during circuit board layout. The following points are emphasized:

- Low ESR / ESL capacitors must be connected close to the IC between VDD and VSS pins and between HB
 and HS pins to support high peak currents being drawn from VDD and HB during the turn-on of the external
 MOSFETs.
- 2. To prevent large voltage transients at the drain of the top MOSFET, a low ESR electrolytic capacitor and a good quality ceramic capacitor must be connected between the MOSFET drain and ground (VSS).
- In order to avoid large negative transients on the switch node (HS) pin, the parasitic inductances between the source of the top MOSFET and the drain of the bottom MOSFET (synchronous rectifier) must be minimized.
- 4. Grounding considerations:
 - a) The first priority in designing grounding connections is to confine the high peak currents that charge and discharge the MOSFET gates to a minimal physical area. This will decrease the loop inductance and minimize noise issues on the gate terminals of the MOSFETs. The gate driver should be placed as close as possible to the MOSFETs.
 - b) The second consideration is the high current path that includes the bootstrap capacitor, the bootstrap diode, the local ground referenced bypass capacitor, and the low-side MOSFET body diode. The bootstrap capacitor is recharged on a cycle-by-cycle basis through the bootstrap diode from the ground referenced VDD bypass capacitor. The recharging occurs in a short time interval and involves high peak current. Minimizing this loop length and area on the circuit board is important to ensure reliable operation.

HS Transient Voltages Below Ground

The HS node will always be clamped by the body diode of the lower external FET. In some situations, board resistances and inductances can cause the HS node to transiently swing several volts below ground. The HS node can swing below ground provided:

- 1. HS must always be at a lower potential than HO. Pulling HO more than -0.3V below HS can activate parasitic transistors resulting in excessive current flow from the HB supply, possibly resulting in damage to the IC. The same relationship is true with LO and VSS. If necessary, a Schottky diode can be placed externally between HO and HS or LO and GND to protect the IC from this type of transient. The diode must be placed as close to the IC pins as possible in order to be effective.
- 2. HB to HS operating voltage should be 15V or less. Hence, if the HS pin transient voltage is -5V, VDD should be ideally limited to 10V to keep HB to HS below 15V.
- 3. Low ESR bypass capacitors from HB to HS and from VDD to VSS are essential for proper operation. The capacitor should be located at the leads of the IC to minimize series inductance. The peak currents from LO and HO can be quite large. Any series inductances with the bypass capacitor will cause voltage ringing at the leads of the IC which must be avoided for reliable operation.

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PACKAGE OPTION ADDENDUM



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PACKAGING INFORMATION

Orderable Device	Status	Package Type	_		Package Qty	Eco Plan	Lead/Ball Finish	MSL Peak Temp	Samples
	(1)		Drawing			(2)		(3)	(Requires Login)
LM5109BMA	ACTIVE	SOIC	D	8	95	TBD	CU SNPB	Level-1-235C-UNLIM	
LM5109BMA/NOPB	ACTIVE	SOIC	D	8	95	Green (RoHS & no Sb/Br)	CU SN	Level-1-260C-UNLIM	
LM5109BMAX	ACTIVE	SOIC	D	8	2500	TBD	CU SNPB	Level-1-235C-UNLIM	
LM5109BMAX/NOPB	ACTIVE	SOIC	D	8	2500	Green (RoHS & no Sb/Br)	CU SN	Level-1-260C-UNLIM	
LM5109BSD	ACTIVE	WSON	NGT	8	1000	TBD	SNPB	Level-1-260C-UNLIM	
LM5109BSD/NOPB	ACTIVE	WSON	NGT	8	1000	Green (RoHS & no Sb/Br)	SN	Level-1-260C-UNLIM	
LM5109BSDX	ACTIVE	WSON	NGT	8	4500	TBD	SNPB	Level-1-260C-UNLIM	
LM5109BSDX/NOPB	ACTIVE	WSON	NGT	8	4500	Green (RoHS & no Sb/Br)	SN	Level-1-260C-UNLIM	

⁽¹⁾ The marketing status values are defined as follows:

ACTIVE: Product device recommended for new designs.

LIFEBUY: TI has announced that the device will be discontinued, and a lifetime-buy period is in effect.

NRND: Not recommended for new designs. Device is in production to support existing customers, but TI does not recommend using this part in a new design.

PREVIEW: Device has been announced but is not in production. Samples may or may not be available.

OBSOLETE: TI has discontinued the production of the device.

(2) Eco Plan - The planned eco-friendly classification: Pb-Free (RoHS), Pb-Free (RoHS Exempt), or Green (RoHS & no Sb/Br) - please check http://www.ti.com/productcontent for the latest availability information and additional product content details.

TBD: The Pb-Free/Green conversion plan has not been defined.

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Green (RoHS & no Sb/Br): TI defines "Green" to mean Pb-Free (RoHS compatible), and free of Bromine (Br) and Antimony (Sb) based flame retardants (Br or Sb do not exceed 0.1% by weight in homogeneous material)

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⁽³⁾ MSL, Peak Temp. -- The Moisture Sensitivity Level rating according to the JEDEC industry standard classifications, and peak solder temperature.





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PACKAGE MATERIALS INFORMATION

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TAPE AND REEL INFORMATION





	Dimension designed to accommodate the component width
	Dimension designed to accommodate the component length
K0	Dimension designed to accommodate the component thickness
W	Overall width of the carrier tape
P1	Pitch between successive cavity centers

QUADRANT ASSIGNMENTS FOR PIN 1 ORIENTATION IN TAPE



*All dimensions are nominal

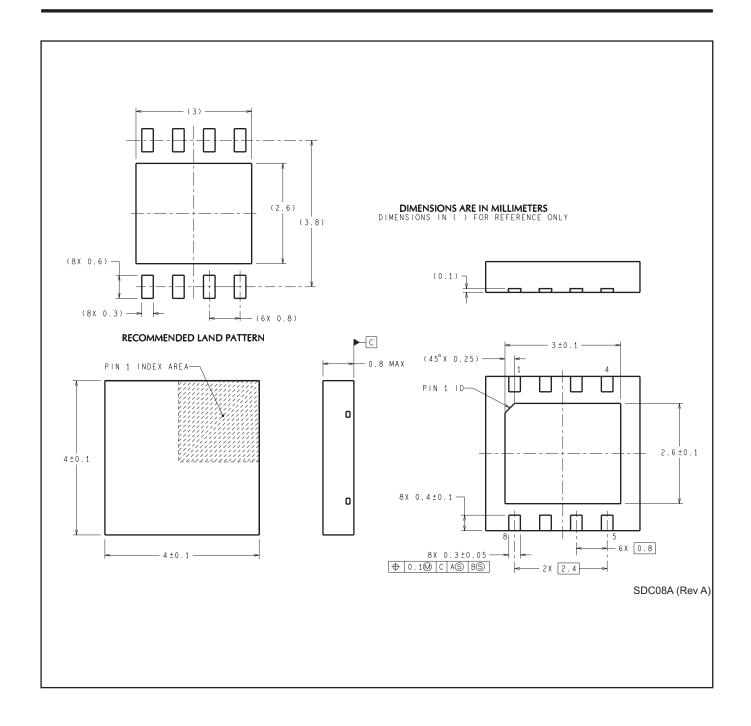
Device	Package Type	Package Drawing		SPQ	Reel Diameter (mm)	Reel Width W1 (mm)	A0 (mm)	B0 (mm)	K0 (mm)	P1 (mm)	W (mm)	Pin1 Quadrant
LM5109BMAX	SOIC	D	8	2500	330.0	12.4	6.5	5.4	2.0	8.0	12.0	Q1
LM5109BMAX/NOPB	SOIC	D	8	2500	330.0	12.4	6.5	5.4	2.0	8.0	12.0	Q1
LM5109BSD	WSON	NGT	8	1000	178.0	12.4	4.3	4.3	1.3	8.0	12.0	Q1
LM5109BSD/NOPB	WSON	NGT	8	1000	178.0	12.4	4.3	4.3	1.3	8.0	12.0	Q1
LM5109BSDX	WSON	NGT	8	4500	330.0	12.4	4.3	4.3	1.3	8.0	12.0	Q1
LM5109BSDX/NOPB	WSON	NGT	8	4500	330.0	12.4	4.3	4.3	1.3	8.0	12.0	Q1

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*All dimensions are nominal

Device	Package Type	Package Drawing	Pins	SPQ	Length (mm)	Width (mm)	Height (mm)
LM5109BMAX	SOIC	D	8	2500	349.0	337.0	45.0
LM5109BMAX/NOPB	SOIC	D	8	2500	349.0	337.0	45.0
LM5109BSD	WSON	NGT	8	1000	203.0	190.0	41.0
LM5109BSD/NOPB	WSON	NGT	8	1000	203.0	190.0	41.0
LM5109BSDX	WSON	NGT	8	4500	349.0	337.0	45.0
LM5109BSDX/NOPB	WSON	NGT	8	4500	349.0	337.0	45.0



D (R-PDSO-G8)

PLASTIC SMALL OUTLINE



NOTES:

- A. All linear dimensions are in inches (millimeters).
- B. This drawing is subject to change without notice.
- Body length does not include mold flash, protrusions, or gate burrs. Mold flash, protrusions, or gate burrs shall not exceed 0.006 (0,15) each side.
- Body width does not include interlead flash. Interlead flash shall not exceed 0.017 (0,43) each side.
- E. Reference JEDEC MS-012 variation AA.



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